

[illegible]

3. A system according to claim 1, wherein:
said memory unit comprises an environmental
sensor for monitoring a temperature and a current,
wherein said control means updates information stored

in said storing means so as to delay an operation timing to said memory unit in response to a notification indicating that a temperature rise around said memory unit or a current value from said environmental sensor exceeds a reference value.

4. A system according to claim 1, wherein:
said memory controller comprises a memory fault detector circuit, wherein said control means, in response to a detection by said detector circuit that a particular group of memory elements fails, updates stored information corresponding to said group of memory elements in said storing means so as to delay an operation timing to said memory unit.

5. A system according to claim 1, wherein:
said memory controller comprises a memory fault detector circuit, wherein said control means, in response to a detection by said detector circuit that a particular group of memory elements fails and that the fault is degraded performance in a particular operation, updates stored information corresponding to said group of memory elements in said storing means so as to delay an operation timing to said memory unit.

6. A memory controller for an information processing system, said memory controller adapted for connection with a processor and a memory unit, comprising:

storing means for storing changeable memory control timing information;

said memory unit includes a mixture of a

said timing information storage means stores memory control timing information corresponding to each said group of memory elements.

said monitoring means includes a memory fault detector circuit for detecting a fault in a particular group of memory elements to output information indicative of the fault, wherein said change control circuit changes stored timing information corresponding to said group of memory elements in response to the output information from said memory fault detector circuit.

the fault detected by said fault detector circuit is degraded performance in a particular operation of a group of memory elements.